Docket No.

251076US2DIV

S PATENT AND TRADEMARK OFFICE IN THE

IN RE APPLICATION OF:

Yuuichi HIRANO, et al.

SERIAL NO:

10/813.038

GAU:

2815

FILED:

March 31, 2004

EXAMINER: WILSON, ALLAN R.

If w 19

FOR:

SEMICONDUCTOR STORAGE DEVICE HAVING HIGH SOFT-ERROR IMMUNITY

# INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

### REFERENCES

- The applicant(s) wish to make of record the references cited in the attached Korean Official Action and listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

#### RELATED CASES

- Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

### **CERTIFICATION**

- Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

## **DEPOSIT ACCOUNT**

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

10/14/2004 CCHAU1 00000134 10813038

01 FC:1806

180.00 OP

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

Gregory J. Maier

Registration No. 25,599

Customer Number

22850

Tel. (703) 413-3000 Fax. (703) 413-2220 (OSMMN 05/03) I:\aTTY\Mm\kongkham\251076.1DS..DOC

Michael E. Monaco Registration No. 52,041

SHEET	1	OF	1

/	/0	12.6.7							
1	OCT	1 2 2004 25							
/-	是	<b>2</b>				SHE	ET 1	OF	1
Form PTO 1449 (Modified)  TRADEL DE DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.	SERIAL NO.					
			251076US2DIV	10/813,038					
		APPLICANT							
LIST OF	REFER	RENCES CITED BY AP	PLICANT	Yuuichi HIRANO, et al.					
			FILING DATE	GROUP					
			March 31, 2004	2815					
				U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS		NG DATE PROPRIAT	E
	AA	5,338,963	08/16/1994	Klaasen et al. (corresponding to JP 7-7089)					
	AB	4,956,815	09/11/1990	Houston					
	AC								
	AD						<del></del>		
	AE								
	AF								
	AG								
	АН								
	ΑI								
	AJ								
	AK								
	AL								
	AM								
	AN				l				
			FO	REIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO			
	AO	11-67933	09/03/1999	JAPAN (w/English abstract)		<del>                                     </del>		Х	$\neg$
-	AP	2001-189389	10/07/2001	JAPAN (w/English abstract)				Х	
	AQ	7-7089	10/01/1995	JAPAN			ļ	Х	
	AR								
	AS								
	ΑT								
	AU								
	AV		<u> </u>						
		OTHER R	EFERENCES (	Including Author, Title, Date, Pertinent	t Pages, e	tc.)			
	AW								
	AX								
	AY								
	AZ				Add	itional Refe	erences sh	eet(s) atta	ched
Examiner				Date Considered					
*Examiner: In conformance	itial if r	reference is considered ot considered. Include o	, whether or no opy of this form	ot citation is in conformance with MPEP 60 n with next communication to applicant.	09; Draw li	ne through	citation if	not in	
·\ATTVMM\KON	SKHVW/,	251076.1449poc							